



The Materials Metrology™ Company

Press Release

## ReVera to Exhibit at SEMICON West 2006

Company to highlight the latest advancements of its VeraFlex™ materials metrology system

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**Sunnyvale, Calif., June 19, 2006** – ReVera Incorporated, the materials metrology company, today announced that it will highlight the latest advancements of its VeraFlex™ materials metrology system – including new applications and capabilities – at SEMICON West 2006. The recently introduced VeraFlex system addresses the increasing demands for materials metrology from development through production on product and monitor wafers. It offers broad measurement capabilities – including thickness, composition, profile, bonding states, interface quality and surface condition – that provide a flexible solution for a wide range of emerging materials metrology requirements for 65 nm, 45 nm and beyond.

“In December ReVera introduced VeraFlex – our second generation materials metrology system,” commented ReVera CEO Dave Ring. “Since that time, VeraFlex has met with rapid market acceptance because of the demonstrated value it provides leading edge semiconductor manufacturers in both development and high-volume production applications. This has allowed us to work closely with our customers to better understand their emerging materials challenges, and to expand applications breadth and capabilities accordingly. We look forward to the opportunity provided by SEMICON West to share these latest advancements.”

ReVera’s activities at the show include:

- **On the show floor:** ReVera will be exhibiting in the Esplanade area at booth #4416 as a part of the Manufacturing Productivity and Effectiveness TECHXPOT (formerly the hall for TIS/Emerging Technologies). Join ReVera at the booth to learn more about the latest advancements of its VeraFlex materials metrology system.
- **Private meetings:** ReVera will be taking advantage of local meeting space for confidential, one-on-one meetings with customers and the press. To reserve a meeting time, customers should contact their local ReVera sales representative or ReVera Incorporated at 408-530-3600.
- **Metrology panel session:** Dave Perloff, ReVera’s Chairman of the Board will be taking part in a SEMI sponsored panel session discussion titled “The Business Climate for Metrology” on Thursday, July 13th from 12:10 pm to 1:10 pm at the Device Scaling TECHXPOT stage in Moscone’s North Hall. Additional panelists include Michele Klein of Applied Materials and John Heaton of Nanometrics. For more information, please visit [www.semi.org](http://www.semi.org).

### About ReVera

ReVera Incorporated is a leading provider of materials metrology solutions for advanced semiconductor processing. Its products allow device manufacturers to measure, monitor and control critical materials properties, enabling them to rapidly integrate and manage the new materials required for 65 nm, 45 nm and beyond. ReVera systems are proven in production in a broad range of applications, and are backed by a global network of applications, field service, sales and logistics personnel. ReVera was established in 2004 as a management-led spin-out from Physical Electronics and its wholly owned subsidiary, Charles Evans and Associates.